

REVIEWER'S REPORT

Manuscript No.: **IJAR-58479**

Title: SRIM-Based Investigation of Heavy-Ions 238U, 132Xe, 84Kr, 56Fe and 40Ar Energy Loss and Penetration in Silicon devices.

Recommendation:

Accept as it is

Accept after minor revision...✓.....

Accept after major revision

Do not accept (*Reasons below*)

Rating	Excel.	Good	Fair	Poor
Originality		✓		
Techn. Quality		✓		
Clarity		✓		
Significance		✓		

Reviewer's ID: JPR- DR PRITI GUPTA

Detailed Reviewer's Report

1. Numerous grammatical and typographical errors should be corrected throughout the manuscript.
2. There are formatting inconsistencies in equations and mathematical symbols.
3. Several tables require improved formatting and unit presentation.
4. The notation of isotopes should be made consistent throughout the manuscript.
5. Spaces before and after units should follow SI conventions.
6. References should be formatted uniformly according to journal style.
7. Some references are old; additional recent literature (2023–2025) on SRIM simulations and radiation effects in semiconductors should be included.